

Normally – OFF Silicon Carbide Junction Transistor

 V_{DS} = 600 V $R_{DS(ON)}$ = 110 mΩ $I_{D (Tc = 25^{\circ}C)}$ = 32 A $h_{FE (Tc = 25^{\circ}C)}$ = 110

Features

- 225°C maximum operating temperature
- Gate Oxide Free SiC Switch
- Exceptional Safe Operating Area
- Excellent Gain Linearity
- Temperature Independent Switching Performance
- Low Output Capacitance
- Positive Temperature Coefficient of R_{DS,ON}
- Suitable for Connecting an Anti-parallel Diode

Advantages

- Compatible with Si MOSFET/IGBT Gate Drive ICs
- > 20 µs Short-Circuit Withstand Capability
- Lowest-in-class Conduction Losses
- High Circuit Efficiency
- Minimal Input Signal Distortion
- · High Amplifier Bandwidth

Package

RoHS Compliant





SMD0.5 / TO - 276 (Hermetic Package)

Applications

- Down Hole Oil Drilling, Geothermal Instrumentation
- Hybrid Electric Vehicles (HEV)
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)
- · Induction Heating
- Uninterruptible Power Supply (UPS)
- Motor Drives

Absolute Maximum Ratings

Parameter	Symbol	Conditions	Values	Unit	
Drain – Source Voltage	V_{DS}	V _{GS} = 0 V	600	V	
Continuous Drain Current	I _D	$T_J = 225^{\circ}C, T_C = 25^{\circ}C$	32	Α	
Continuous Gate Current	I_{GM}		2	Α	
Turn-Off Safe Operating Area	RBSOA	T_{VJ} = 225°C, I_{G} = 1.5 A, Clamped Inductive Load	$I_{D,max} = 16$ @ $V_{DS} \le V_{DSmax}$	Α	
Short Circuit Safe Operating Area	SCSOA	T_{VJ} = 225°C, I_G = 1.5 A, V_{DS} = 400 V, Non Repetitive	>20	μs	
Reverse Gate – Source Voltage	V _{GS}	·	30	V	
Reverse Drain – Source Voltage	V_{DS}		40	V	
Power Dissipation	P_{tot}	$T_J = 225^{\circ}C, T_C = 25^{\circ}C$	330	W	
Operating and Storage Temperature	T_{j},T_{stg}		-55 to 225	°C	

Electrical Characteristics

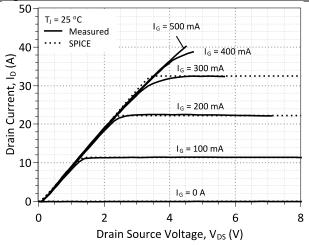
Parameter	Symbol	Conditions -	Values		l lmi4	
			min.	typ.	max.	Unit
On Characteristics						
Drain – Source On Resistance	R _{DS(ON)}	$I_D = 16 \text{ A}, I_G = 500 \text{ mA}, T_j = 25 \text{ °C}$		110		mΩ
		$I_D = 16 \text{ A}, I_G = 1000 \text{ mA}, T_j = 175 °C$		170		
		$I_D = 16 \text{ A}, I_G = 1000 \text{ mA}, T_j = 250 ^{\circ}\text{C}$		260		
Gate Forward Voltage	$V_{GS(FWD)}$	$I_G = 500 \text{ mA}, T_j = 25 \text{ °C}$		3		V
		$I_G = 500 \text{ mA}, T_j = 250 \text{ °C}$		2.6		
DC Current Gain	β	$V_{DS} = 5 \text{ V}, I_{D} = 20 \text{ A}, T_{j} = 25 ^{\circ}\text{C}$	80	110		
		V_{DS} = 5 V, I_{D} = 20 A, T_{j} = 250 °C	50	75		
Off Characteristics						
		$V_R = 600 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 25 \text{ °C}$		10	100	
Drain Leakage Current	$I_{ extsf{DSS}}$	$V_R = 600 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 175 ^{\circ}\text{C}$		40	400	μΑ
		$V_R = 600 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 250 ^{\circ}\text{C}$		100	600	•



Electrical Characteristics

Parameter	Symbol	Conditions	Values			1114
			min.	typ.	max.	Unit
Dynamic Characteristics						
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V}, V_D = 35 \text{ V}, f = 1 \text{ MHz}$		1535		pF
Reverse Transfer/Output Capacitance	C _{rss} /C _{oss}	V _D = 35 V, f = 1 MHz		157		pF
Output Capacitance Stored Energy	E _{oss}	$V_{GS} = 0 \text{ V}, V_D = 35 \text{ V}, f = 1 \text{ MHz}$		96		nJ
Switching Characteristics						
Turn On Delay Time	$t_{d(on)}$			15		ns
Rise Time	t _r	$V_{DD} = 400 \text{ V}, I_D = 16 \text{ A},$		40		ns
Turn Off Delay Time	$t_{d(off)}$	R_G = 22 Ω , C_G = 9 nF Single-Level Gate Driver V_{GS} = -8/15 V , T_J = 175 °C Refer to Figure 11 for gate drive current waveforms		70		ns
Fall Time	t _f			80		ns
Turn-On Energy Per Pulse	E _{on}			65		μJ
Turn-Off Energy Per Pulse	E _{off}			365		μJ
Total Switching Energy	E _{ts}			430		μJ
Turn On Delay Time	t _{d(on)}	V_{DD} = 400 V, I_{D} = 16 A, R_{G} = 22 Ω , C_{G} = 9 nF Single-Level Gate Driver V_{GS} = -8/15 V, T_{J} = 250 °C Refer to Figure 11 for gate drive current waveforms		10		ns
Rise Time	t _r			40		ns
Turn Off Delay Time	$t_{d(off)}$			85		ns
Fall Time	t _f			85		ns
Turn-On Energy Per Pulse	E _{on}			65		μJ
Turn-Off Energy Per Pulse	E _{off}			395		μJ
Total Switching Energy	E _{ts}	7		460		μJ
Thermal Characteristics						
Thermal resistance, junction - case	R_{thJC}			0.6		°C/W







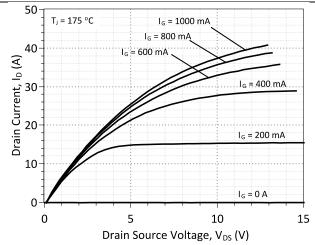


Figure 2: Typical Output Characteristics at 175 °C



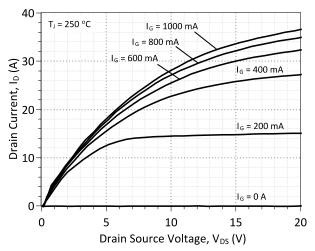


Figure 3: Typical Output Characteristics at 250 °C

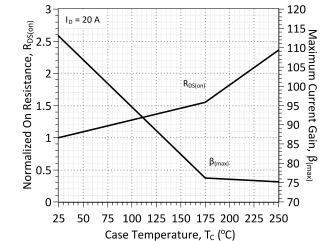


Figure 5: Normalized On-Resistance and Current Gain vs. Temperature

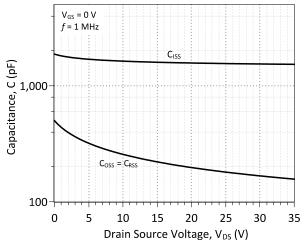


Figure 7: Typical Capacitance vs Drain-Source Voltage

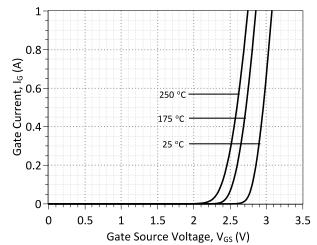


Figure 4: Typical Gate Source I-V Characteristics vs. Temperature

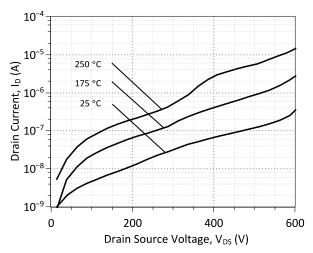


Figure 6: Typical Blocking Characteristics

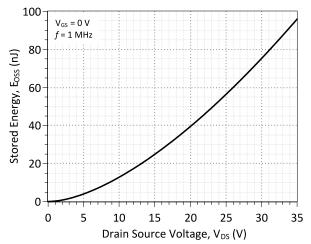
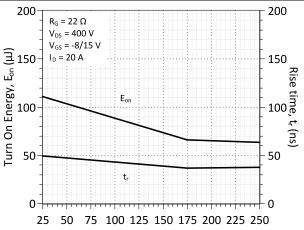


Figure 8: Output Capacitance Stored Energy







Case Temperature, T_C (°C) Figure 9: Typical Turn On Energy Losses and Switching Times vs. Temperature

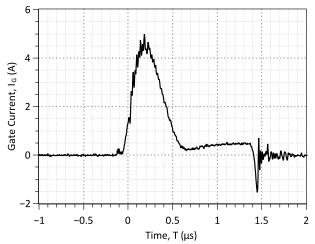


Figure 11: Typical Gate Current Waveform

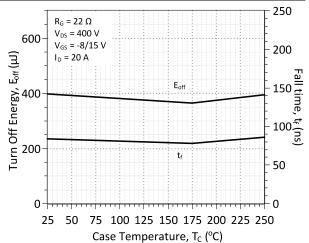


Figure 10: Typical Turn Off Energy Losses and Switching Times vs. Temperature



Gate Drive Theory of Operation

The SJT transistor is a current controlled transistor which requires a positive gate current for turn-on as well as to remain in on-state. An ideal gate current waveform for ultra-fast switching of the SJT, while maintaining low gate drive losses, is shown in Figure 12.

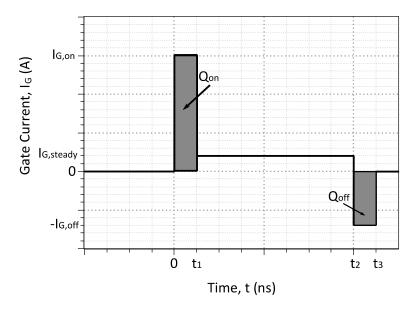


Figure 12: Idealized Gate Current Waveform

Gate Currents, $I_{G,pk}/I_{G,pk}$ and Voltages during Turn-On and Turn-Off

An SJT is rapidly switched from its blocking state to on-state, when the necessary gate charge, Q_G , for turn-on is supplied by a burst of high gate current, $I_{G,on}$, until the gate-source capacitance, C_{GS} , and gate-drain capacitance, C_{GD} , are fully charged.

$$I_{G,on} * t_1 \ge Q_{gs} + Q_{gd}$$

The $I_{G,pon}$ pulse should ideally terminate, when the drain voltage falls to its on-state value, in order to avoid unnecessary drive losses during the steady on-state. In practice, the rise time of the $I_{G,on}$ pulse is affected by the parasitic inductances, L_{par} in the package and drive circuit. A voltage developed across the parasitic inductance in the source path, L_s , can de-bias the gate-source junction, when high drain currents begin to flow through the device. The applied gate voltage should be maintained high enough, above the $V_{GS,ON}$ level to counter these effects.

A high negative peak current, $-I_{G,off}$ is recommended at the start of the turn-off transition, in order to rapidly sweep out the injected carriers from the gate, and achieve rapid turn-off. While satisfactory turn off can be achieved with $V_{GS} = 0$ V, a negative gate voltage V_{GS} may be used in order to speed up the turn-off transition.

Steady On-State

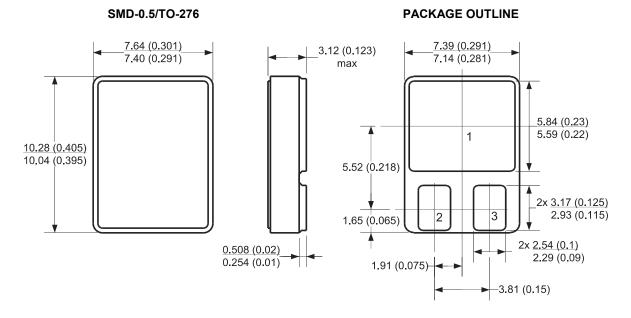
After the device is turned on, I_G may be advantageously lowered to $I_{G,steady}$ for reducing unnecessary gate drive losses. The $I_{G,steady}$ is determined by noting the DC current gain, h_{FE} , of the device.

The desired $I_{G,steady}$ is determined by the peak device junction temperature T_J during operation, drain current I_D , DC current gain h_{FE} , and a 50 % safety margin to ensure operating the device in the saturation region with low on-state voltage drop by the equation:

$$I_{G,steady} \approx \frac{I_D}{h_{FE}(T,I_D)} * 1.5$$



Package Dimensions:



NOTE

- 1. CONTROLLED DIMENSION IS MILLIMETER. DIMENSION IN BRACKET IS INCH.
- 2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS

Revision History				
Date	Revision Comments		Supersedes	
2014/08/25	5	Updated Electrical Characteristics		
2014/03/19	4	Updated Gate Drive Section		
2014/02/14	3	Updated Electrical Characteristics		
2013/12/19	2	Updated Gate Drive Section		
2013/11/18	1	Updated Electrical Characteristics		
2012/08/24	0	Initial release		

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SPICE Model Parameters

This is a secure document. Please copy this code from the SPICE model PDF file on our website (http://www.genesicsemi.com/images/hit_sic/sjt/2N7640-GA SPICE.pdf) into LTSPICE (version 4) software for simulation of the 2N7640-GA.

```
MODEL OF GeneSiC Semiconductor Inc.
     $Revision: 1.2
                                $
     $Date: 23-JUN-2014
     GeneSiC Semiconductor Inc.
     43670 Trade Center Place Ste. 155
    Dulles, VA 20166
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* These models are provided "AS IS, WHERE IS, AND WITH NO WARRANTY
* OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED
* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
* PARTICULAR PURPOSE."
* Models accurate up to 2 times rated drain current.
.model 2N7640 NPN
+ IS
         6.03E-47
+ ISE
          1.72E-28
          3.23
+ EG
          122
+ BF
+ BR
          0.55
+ IKF
         300
+ NF
         1.868
+ NE
+ RB
          2.50
+ RE
          0.088
+ RC
          0.01
+ CJC
          5.68E-10
+ VJC
          2.978967839
+ MJC
         0.466424924
+ CJE
          1.72E-09
          2.77859888
+ VJE
+ MJE
         0.48415
+ XTI
          3
+ XTB
          -0.78
+ TRC1
          7.00E-02
+ VCEO
          600
+ ICRATING 32
          GeneSiC Semiconductor
+ MFG
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* End of 2N7640-GA SPICE Model